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(12) **United States Design Patent**  
**Teranishi et al.**

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(54) **PROBE PIN**  
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(JP)  
(\*\*) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (10) Cl.** ..... **10-04**

(Continued)

(52) **U.S. Cl.**  
USPC ..... **D10/80**

(58) **Field of Classification Search**  
USPC ..... D10/78, 80; D13/133, 154  
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1/06711; G01R 1/06716; G01R 1/06722;  
G01R 1/06727; G01R 1/06733; G01R  
1/06738; G01R 1/06744; G01R 1/0675;  
G01R 1/06766; G01R 1/06772; G01R  
1/06777; G01R 1/06783; G01R 1/0678  
See application file for complete search history.

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Goldstein & Fox P.L.L.C.

(57) **CLAIM**  
The ornamental design for a probe pin, as shown and  
described.

**DESCRIPTION**

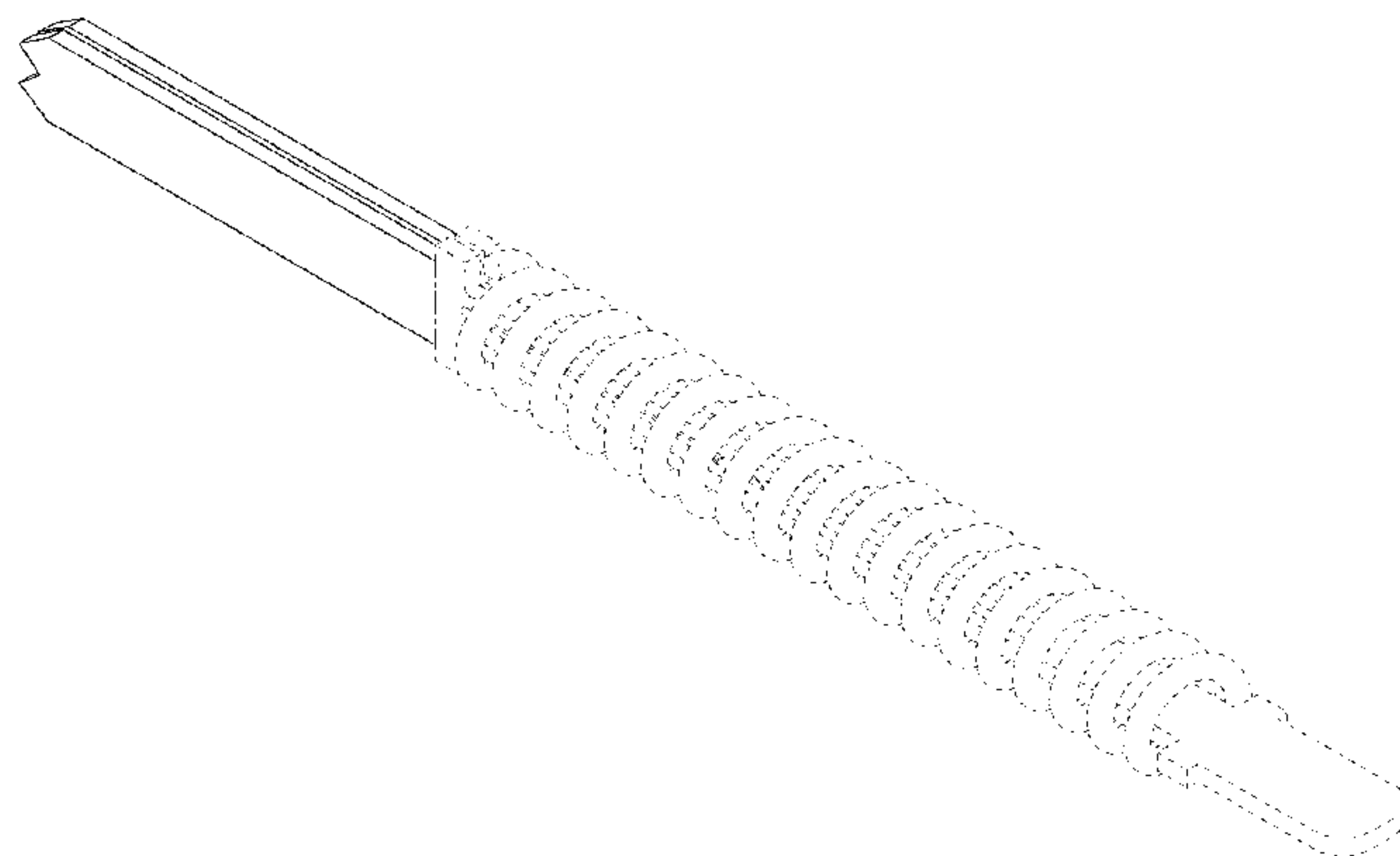
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FIG. 1 is a perspective view of a probe pin;  
FIG. 2 is a front elevation view thereof;  
FIG. 3 is a rear elevation view thereof;  
FIG. 4 is a left side view thereof;  
FIG. 5 is a right side view thereof;  
FIG. 6 is a top plan view thereof; and,  
FIG. 7 is a bottom plan view thereof.  
The broken lines depict the environmental subject matter  
only and form no part of the claimed design. The dot-dash  
line represents the boundary of the claimed design.

**1 Claim, 3 Drawing Sheets**



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Fig. 1

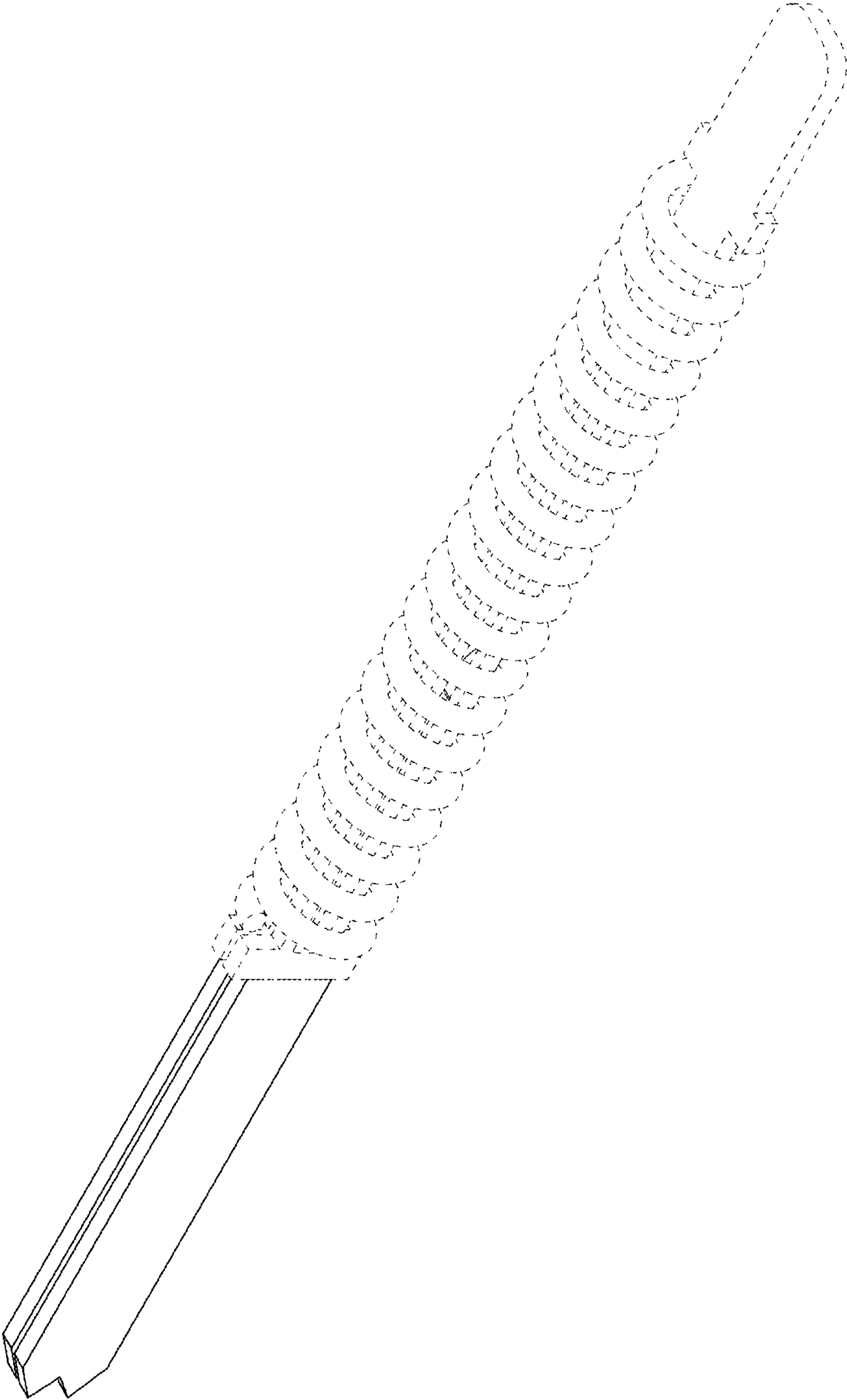


Fig. 2

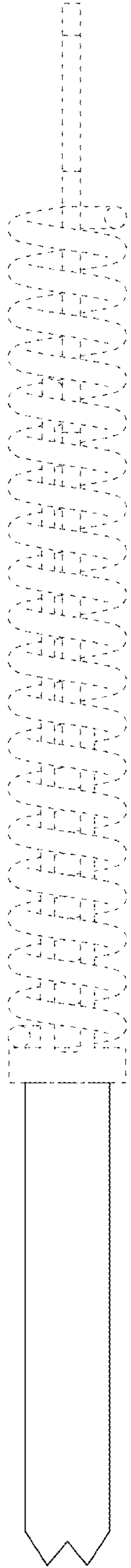


Fig. 3

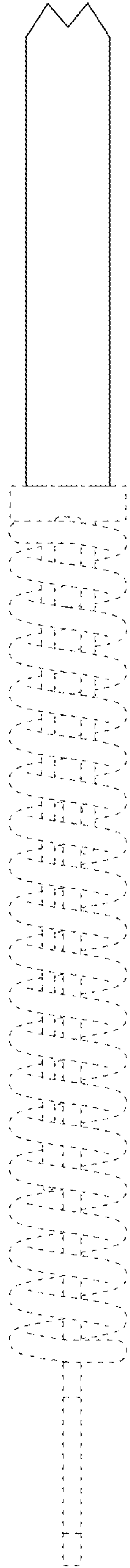


Fig. 4

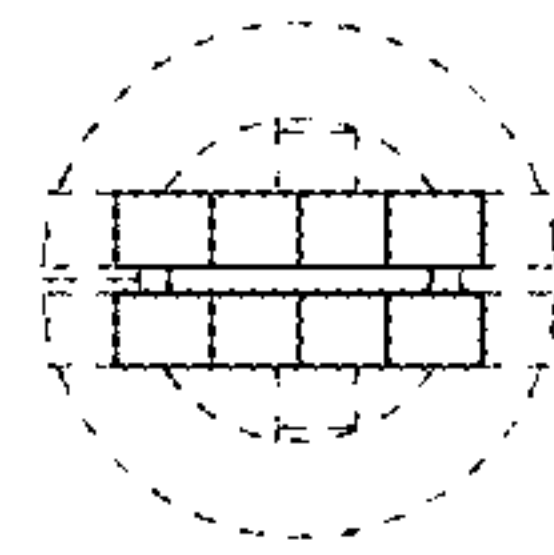
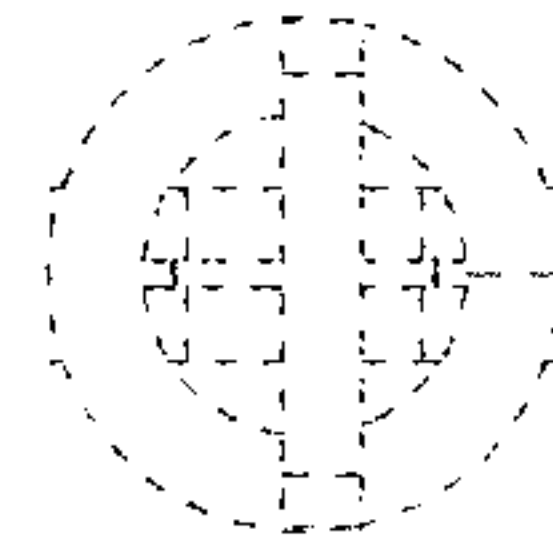


Fig. 5



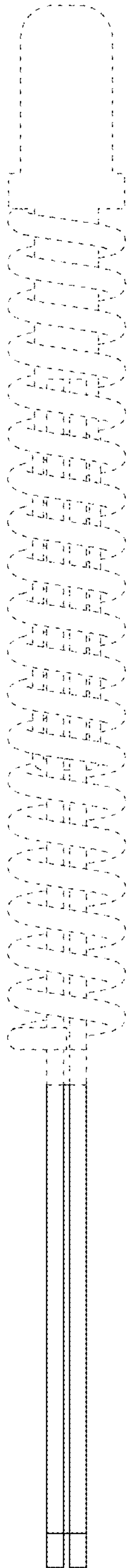


Fig. 6

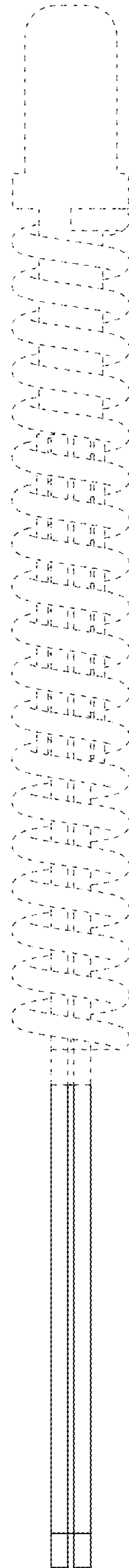


Fig. 7